#### Mosaic: Exploiting the Spatial Locality of Process Variation to Reduce Refresh Energy in On-Chip eDRAM Modules

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Aditya Agrawal, Amin Ansari and Josep Torrellas

TATATA CONTRACTOR

http://iacoma.cs.uiuc.edu

illinois.edu

- eDRAM
- Periodic Refresh Requirement
- Refresh Reduction Techniques

#### MOTIVATION



### eDRAM

- A 1T1C dynamic memory technology.
- The bit is stored as charge on the capacitor.
- Area and leakage energy savings.
- Increasing adoption in commercial processors: IBM POWER 7, POWER 8, Intel Haswell.
- Constraint: The charge on the capacitor has to be refreshed periodically.



## Periodic Refresh Requirement

- Blocks normal accesses.
- Has temperature dependence (2x every 10 °C increase).
- Susceptible to device variations.
- Refresh rate in DRAM ~ once in 64 msec (at 85 °C).
- Refresh rate in eDRAM ~ once in 100  $\mu$ sec (at 95 °C).
- Impacts energy and performance.



## **Refresh Reduction Techniques**

- Access Patterns to Memory
  - Smart Refresh (MICRO 2007): DRAM
  - Refrint (HPCA 2013): eDRAM
- Variation in Retention Times
  - RAPID (HPCA 2006):
  - Hi-ECC (ISCA 2010):
  - RAIDR (ISCA 2012):
  - Mosaic (HPCA 2014):

DRAM eDRAM DRAM eDRAM



## Contribution

- Expose the on chip spatial locality in retention times.
  A mathematical model accessible to architects.
- Exploit the spatial locality for refresh reduction.
  - A hardware only solution.
  - Low area overhead (2%).
  - Significant refresh reduction (20x).



- eDRAM Cell Retention Time
- Retention Time Distribution
- Bulk Distribution, Tail Distribution
- Main Idea

## BACKGROUND

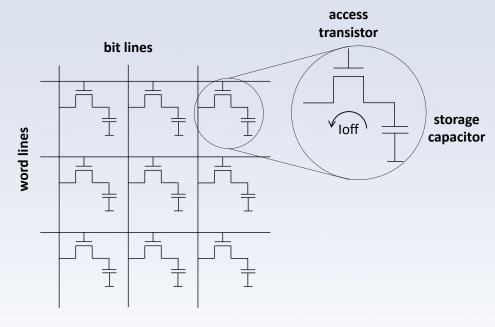


#### eDRAM Cell Retention Time

$$T_{ret} = A * 10^{(Vt*B)} sec$$

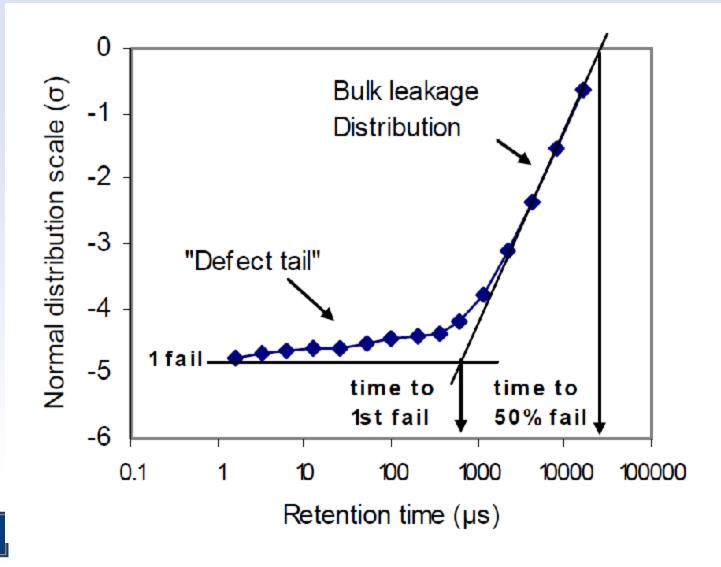
Using published data from IBM at 65 nm,  $T_{ret} \sim 25$  msec.

However, in practice eDRAMs are refreshed at ~ 50-100 usec.





### **Retention Time Distribution**



# **Bulk Distribution**

- Area under the curve from (-4  $\sigma$ ,  $\infty$ ).
  - 99.9968% of the cells.
- Follows a log-normal distribution.
- Caused by process variation in  $V_t$  of the access transistor.
  - Includes systematic and random components.

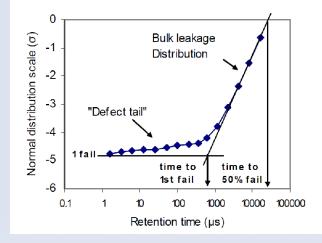
We also know,

- V<sub>t</sub> variation has a normal distribution.
- $-\log_{10}(T_{ret}) = V_t/B + \log_{10}(A)$

Therefore,

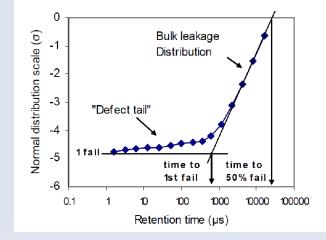
– Normal distribution in  $V_t \rightarrow Log$  normal distribution in  $T_{ret.}$ 





# Tail Distribution

- Area under the curve from  $(-\infty, -4 \sigma)$ . - 0.0031% of the cells (31 ppm).
- Follows a log normal distribution.
- Caused by random manufacturing defects.
- Only a small fraction (3 ppm) is considered defective.





## Main Idea

- $T_{ret}$  is a function of  $V_t$ .
- V<sub>t</sub> variation has spatial locality (systematic component).

Therefore,

- T<sub>ret</sub> will have spatial locality.
- Exploiting this spatial locality can reduce refresh energy at low area and energy overheads.



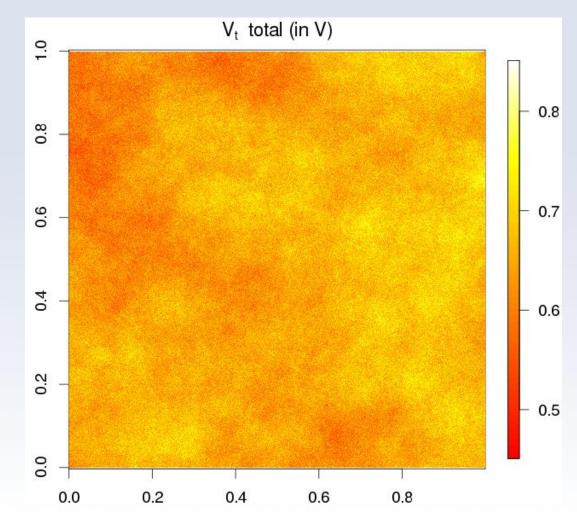
- Spatial Map of Retention Times
- Opportunity & Tradeoffs

#### EXPLOITING SPATIAL LOCALITY



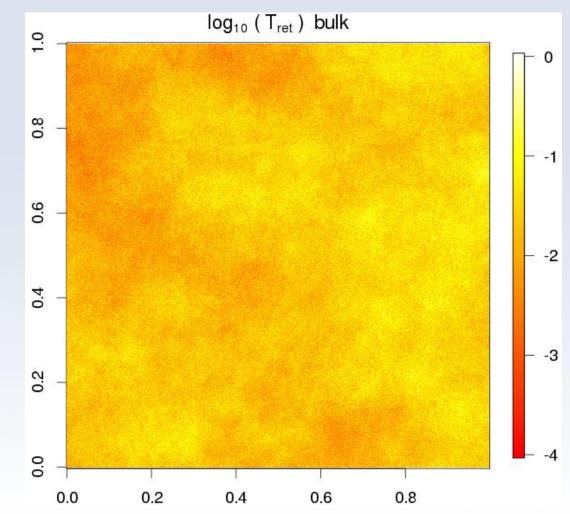
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- Obtain a spatial map of V<sub>t</sub> using VARIUS.
- Includes the systematic and random components of  $V_t$  variation.



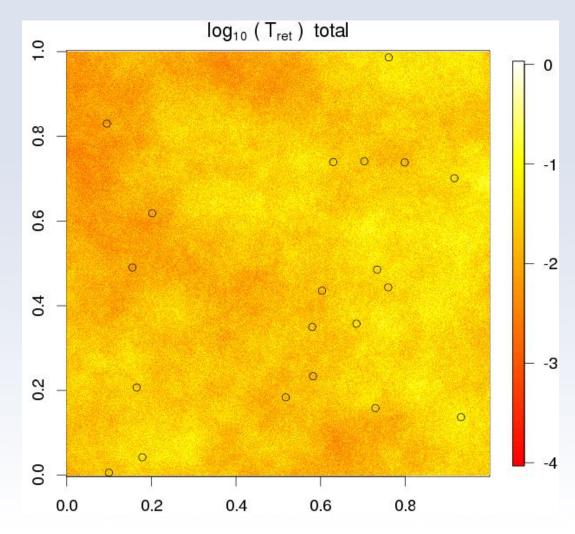


- Cell by cell translation from  $V_t$  values to  $T_{ret}$  for the bulk distribution.
- Spatial map remains the same, the scale changes from linear to log<sub>10</sub>.



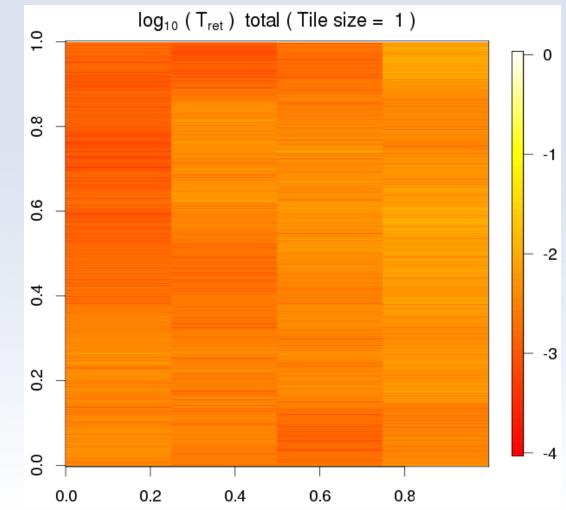


- From IBM data: 20 ppm cells follow the tail distribution.
- Superimposing the tail distribution on the bulk distribution gives the total per-cell  $T_{ret}$  distribution.





- Memory is accessed at a line granularity.
- We obtain a per-line  $T_{ret}$  distribution by taking the minima of the cells in the line.



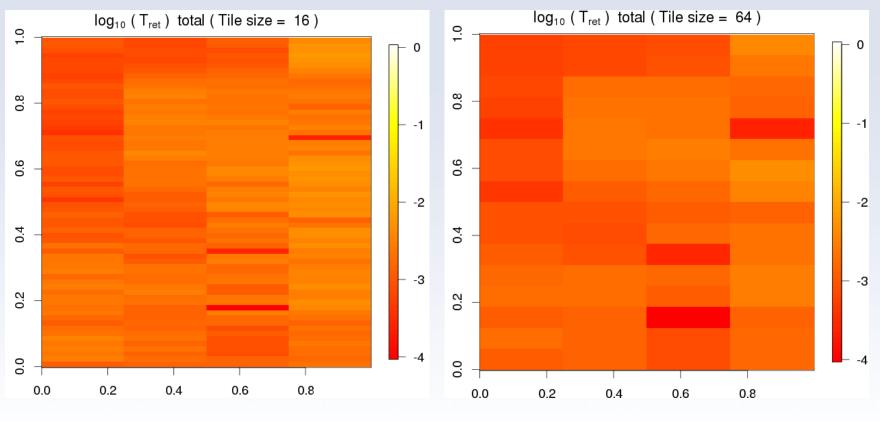


# Opportunity

- Lower bound on the number of refreshes
  - Profile, track and refresh each line at its own rate.
  - Huge area and energy overheads.
- A better solution (**Mosaic**): Exploit spatial locality of T<sub>ret</sub>
  - Logically group co-located lines into tiles.
  - Profile each tile and save the information (in a SRAM).
  - Track (using counters) and refresh each tile at its own rate.
  - Potentially with small area and energy overheads.



### Mosaic of Tiles



Mosaic with Tile Size = 16

Mosaic with Tile Size = 64



#### Tradeoffs

Refresh energy savings - counter size - tile size.

- Small tiles => high refresh savings, high area overheads.
- Small counters => low refresh savings, low area overheads.

#### Next,

- A simple HW solution to track and refresh each tile.
- Best combination of tile size and counter size (Mosaic).
- Compare Mosaic against baseline and lower bound.



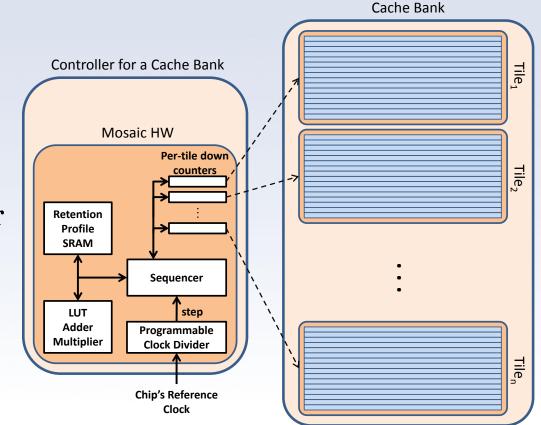
- Mosaic Hardware
- Mosaic Operation

### ARCHITECTURE



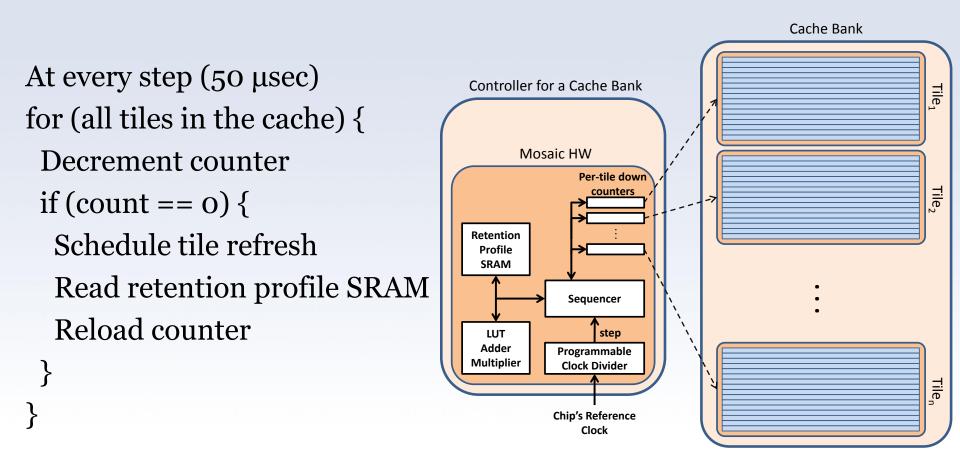
### Mosaic Refresh Hardware

- Augment the cache controller
- SRAM with a profile of tile retention times.
- Logic to track and trigger per tile refresh.





## **Mosaic Operation**





- Architectural Parameters
- Tools & Applications
- Design Comparison

#### **EVALUATION SETUP**



## **Evaluation Setup**

Architectural parameters	
Chip	CMP with 16 2-issue cores
IL1/DL1	32 KB, private
L2	256 KB, private
L3 (eDRAM)	16 MB, 16 banks, shared
L3 bank	1 MB
Network	4 x 4 torus
Coherence	MESI directory at L3



## **Evaluation Setup**

Tools & Applications	
Architectural Simulator	SESC
Timing & Power	McPAT & CACTI
Synthesis	Design Compiler
Statistics	R
Variation	VARIUS
Applications	SPLASH-2, PARSEC



# Design Comparison

- Baseline:
  - All lines refreshed at 50  $\mu$ sec.
- RAIDR:
  - Applied to eDRAMs.
  - Lines refreshed at 50, 100 or 200  $\mu sec.$
- Mosaic:
  - Tile size of 32 lines, 6 bit counter per tile.
  - L3 area overhead of 2%.
- Ideal (lower bound):
  - Tile size of 1.

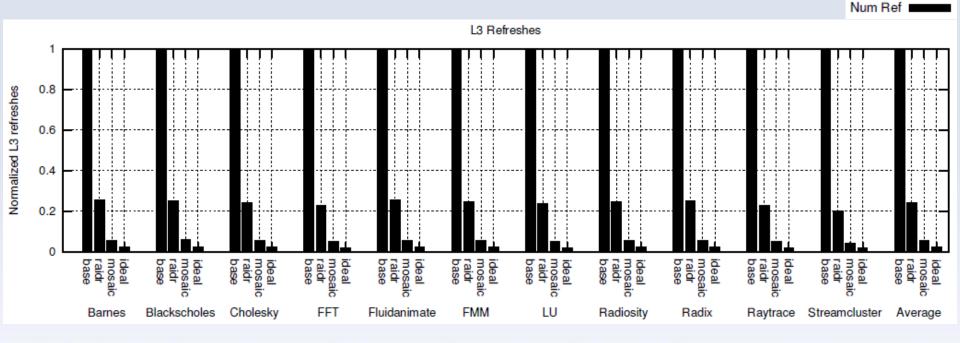


- Refresh Count
- Execution Time
- L3 Energy

### **EVALUATION**



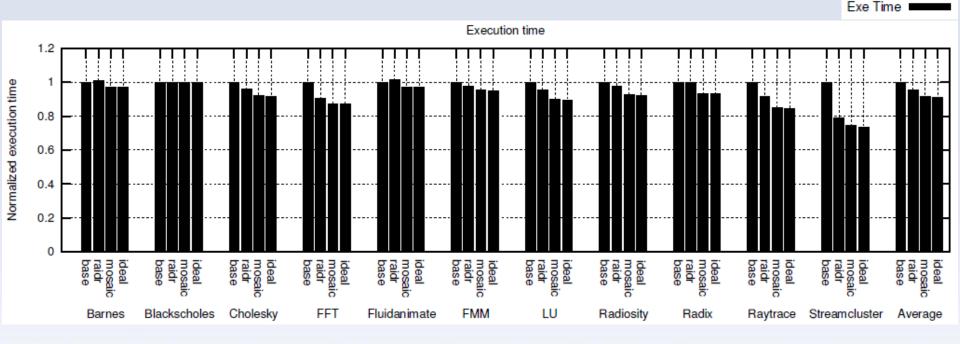
#### **Refresh Count**



- RAIDR reduces the number of L3 refreshes by 4x.
- Mosaic reduces the number of L3 refreshes by 20x.
- Mosaic is within 2.5x of the lower bound (ideal).



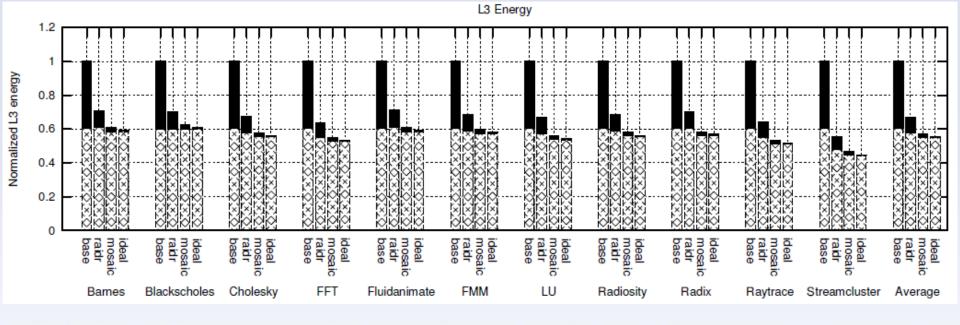
#### **Execution** Time



- Performance improves because of reduced cache blocking.
- Mosaic reduces execution time by 9%.
- Ideal reduces execution time by 10%.







- L3 energy reduction comes from savings in refresh energy and leakage energy.
- Mosaic saves 43% of L3 energy.



Refresh

Leakage Leakage Dynamic

## Conclusion

- Exposed the on chip spatial locality of retention times.
   A mathematical model accessible to architects.
- Exploited the spatial locality for refresh reduction.
  - A hardware only solution.
  - Low L3 area overhead (2%).
  - Significant refresh reduction (20x).
  - Saves 43% energy in L3.



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